## The RF MOSFET Line **RF Power Field-Effect Transistor MRF148A** N–Channel Enhancement–Mode Designed for power amplifier applications in industrial, commercial and amateur radio equipment to 175 MHz. Superior High Order IMD • Specified 50 Volts, 30 MHz Characteristics Output Power = 30 Watts 30 W, to 175 MHz **N-CHANNEL MOS** Power Gain = 18 dB (Typ) LINEAR RF POWER Efficiency = 40% (Typ) FET • IMD<sub>(d3)</sub> (30 W PEP) — −35 dB (Typ) • IMD(d11) (30 W PEP) --- 60 dB (Typ) • 100% Tested For Load Mismatch At All Phase Angles With 30:1 VSWR • Lower Reverse Transfer Capacitance (3.0 pF Typical) DQ Go CASE 211-07, STYLE 2 ς

#### MAXIMUM RATINGS

SS         120           GO         120           S         ±40           6.0	Vdc Vdc Vdc Adc
S ±40	Vdc
6.0	Adc
) 115 0.66	Watts W/°C
g -65 to +1	150 °C
200	°C
	g -65 to +7

Characteristic	Symbol	Мах	Unit
Thermal Resistance, Junction to Case	R <sub>θJC</sub>	1.52	°C/W

NOTE – <u>CAUTION</u> – MOS devices are susceptible to damage from electrostatic charge. Reasonable precautions in handling and packaging MOS devices should be observed.



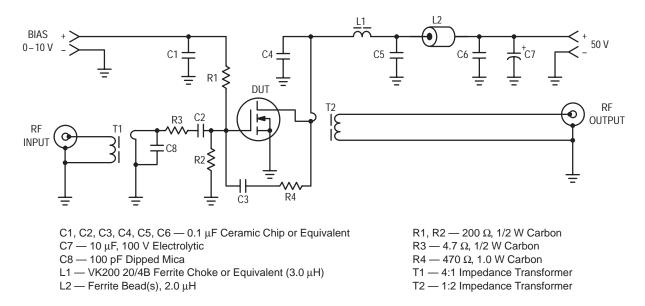
Characteristic	Symbol	Min	Тур	Max	Unit
DFF CHARACTERISTICS					
Drain–Source Breakdown Voltage ( $V_{GS}$ = 0, $I_D$ = 10 mA)	V(BR)DSS	125	—	—	Vdc
Zero Gate Voltage Drain Current (V <sub>DS</sub> = 50 V, V <sub>GS</sub> = 0)	IDSS		—	1.0	mAdc
Gate–Body Leakage Current (V <sub>GS</sub> = 20 V, V <sub>DS</sub> = 0)	IGSS		—	100	nAdc
ON CHARACTERISTICS					-
Gate Threshold Voltage (V_{DS} = 10 V, I_{D} = 10 mA)	V <sub>GS(th)</sub>	1.0	2.5	5.0	Vdc
Drain–Source On–Voltage ( $V_{GS}$ = 10 V, I <sub>D</sub> = 2.5 A)	V <sub>DS(on)</sub>	1.0	3.0	5.0	Vdc
Forward Transconductance (V <sub>DS</sub> = 10 V, I <sub>D</sub> = 2.5 A)	9fs	0.8	1.2	-	mhos
DYNAMIC CHARACTERISTICS					-
Input Capacitance (V_{DS} = 50 V, V_{GS} = 0, f = 1.0 MHz)	C <sub>iss</sub>		62	—	pF
Output Capacitance (V_{DS} = 50 V, V_{GS} = 0, f = 1.0 MHz)	C <sub>OSS</sub>		35	-	pF
Reverse Transfer Capacitance (V_{DS} = 50 V, V_{GS} = 0, f = 1.0 MHz)	C <sub>rss</sub>		3.0	-	pF
FUNCTIONAL TESTS (SSB)					-
Common Source Amplifier Power Gain(30 MHz)(VDD = 50 V, Pout = 30 W (PEP), IDQ = 100 mA)(175 MHz)	G <sub>ps</sub>	_	18 15	-	dB
Drain Efficiency         (30 W PEP)           (V <sub>DD</sub> = 50 V, f = 30 MHz, I <sub>DQ</sub> = 100 mA)         (30 W CW)	η	_	40 50		%
Intermodulation Distortion $(V_{DD} = 50 \text{ V}, P_{out} = 30 \text{ W} (PEP),$ $f = 30; 30.001 \text{ MHz}, I_{DQ} = 100 \text{ mA})$	IMD <sub>(d3)</sub> IMD <sub>(d11)</sub>		-35 -60		dB
Load Mismatch (V <sub>DD</sub> = 50 V, P <sub>out</sub> = 30 W (PEP), f = 30; 30.001 MHz, I <sub>DQ</sub> = 100 mA, VSWR 30:1 at all Phase Angles)	Ψ	No Degradation in Output Power			

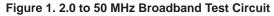
#### **ELECTRICAL CHARACTERISTICS** (T<sub>C</sub> = $25^{\circ}$ C unless otherwise noted.)

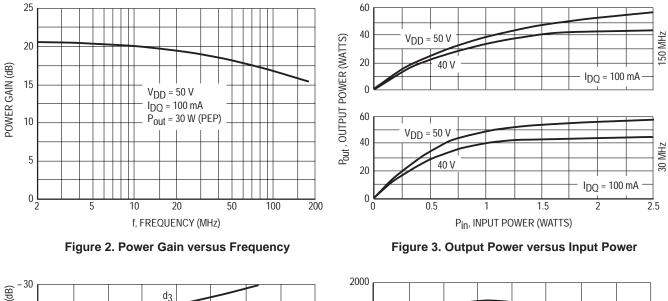
Intermodulation Distortion (1) and Power Gain	GPS	_	20	_	dB
(V <sub>DD</sub> = 50 V, P <sub>out</sub> = 10 W (PEP), f1 = 30 MHz,	IMD <sub>(d3)</sub>	_	-50	_	
f2 = 30.001 MHz, I <sub>DQ</sub> = 1.0 A)	IMD(d9-13)	-	-70	_	

NOTE:

1. To MIL-STD-1311 Version A, Test Method 2204B, Two Tone, Reference Each Tone.







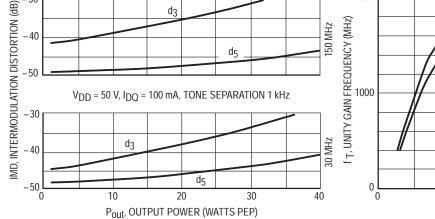


Figure 4. IMD versus Pout



2

ID, DRAIN CURRENT (AMPS)

1

V<sub>DS</sub> = 15 V

3

 $V_{DS} = 30 V$ 

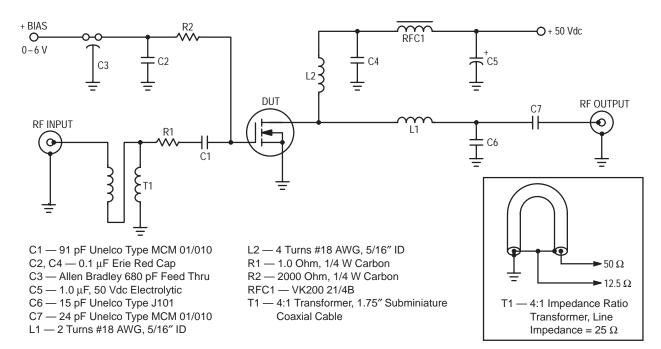


Figure 6. 150 MHz Test Circuit

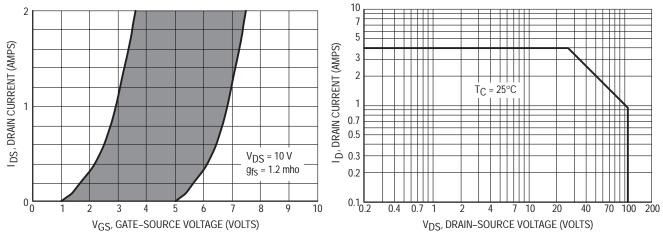
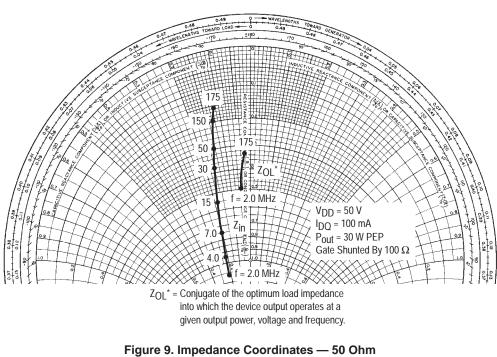


Figure 7. Gate Voltage versus Drain Current

Figure 8. DC Safe Operating Area (SOA)



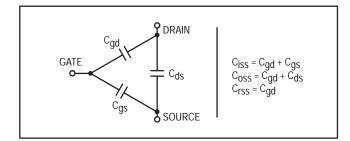
Characteristic Impedance

#### **MOSFET CAPACITANCES**

The physical structure of a MOSFET results in capacitors between the terminals. The metal oxide gate structure determines the capacitors from gate–to–drain ( $C_{gd}$ ), and gate–to–source ( $C_{gs}$ ). The PN junction formed during the fabrication of the RF MOSFET results in a junction capacitance from drain–to–source ( $C_{ds}$ ).

These capacitances are characterized as input ( $C_{iSS}$ ), output ( $C_{OSS}$ ) and reverse transfer ( $C_{rSS}$ ) capacitances on data sheets. The relationships between the inter-terminal capacitances and those given on data sheets are shown below. The  $C_{iSS}$  can be specified in two ways:

- 1. Drain shorted to source and positive voltage at the gate.
- Positive voltage of the drain in respect to source and zero volts at the gate. In the latter case the numbers are lower. However, neither method represents the actual operating conditions in RF applications.



#### LINEARITY AND GAIN CHARACTERISTICS

In addition to the typical IMD and power gain data presented, Figure 5 may give the designer additional information on the capabilities of this device. The graph represents the small signal unity current gain frequency at a given drain current level. This is equivalent to f<sub>T</sub> for bipolar transistors.

Since this test is performed at a fast sweep speed, heating of the device does not occur. Thus, in normal use, the higher temperatures may degrade these characteristics to some extent.

#### **DRAIN CHARACTERISTICS**

One figure of merit for a FET is its static resistance in the full–on condition. This on–resistance,  $V_{DS(on)}$ , occurs in the linear region of the output characteristic and is specified under specific test conditions for gate–source voltage and drain current. For MOSFETs,  $V_{DS(on)}$  has a positive temperature coefficient and constitutes an important design consideration at high temperatures, because it contributes to the power dissipation within the device.

#### **GATE CHARACTERISTICS**

The gate of the RF MOSFET is a polysilicon material, and is electrically isolated from the source by a layer of oxide. The input resistance is very high — on the order of  $10^9$  ohms — resulting in a leakage current of a few nanoamperes.

Gate control is achieved by applying a positive voltage slightly in excess of the gate-to-source threshold voltage, VGS(th).

**Gate Voltage Rating** — Never exceed the gate voltage rating. Exceeding the rated  $V_{GS}$  can result in permanent damage to the oxide layer in the gate region.

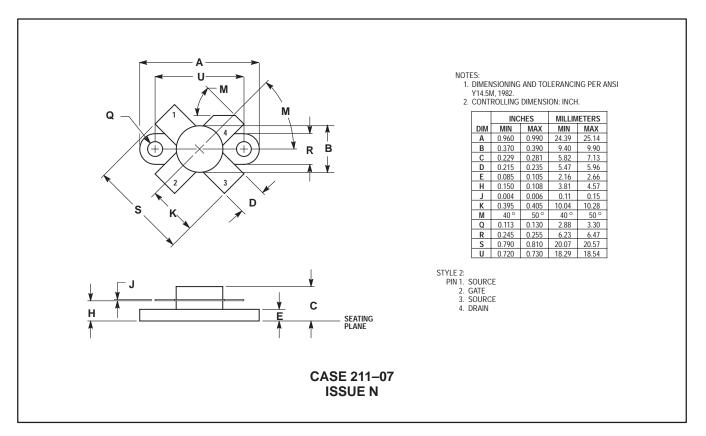
**Gate Termination** — The gates of these devices are essentially capacitors. Circuits that leave the gate open-circuited or floating should be avoided. These conditions can result in turn-on of the devices due to voltage build-up on the input capacitor due to leakage currents or pickup.

**Gate Protection** — These devices do not have an internal monolithic zener diode from gate-to-source. If gate protection is required, an external zener diode is recommended.

Emitter Base V(BR)CES VCBO IC ICES IEBO VBE(on) VCE(sat) Cib Cob	Source Gate V(BR)DSS VDGO ID IDSS IGSS VGS(th) VDS(on) Ciss Coss	
$R_{CE(sat)} = \frac{V_{CE(sat)}}{I_C}$	 rDS(on) =	V <sub>DS(on)</sub> I <sub>D</sub>

#### EQUIVALENT TRANSISTOR PARAMETER TERMINOLOGY

### PACKAGE DIMENSIONS



# NOTES

## NOTES

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